

Integrated circuits - Measurement of electromagnetic immunity - Part 1: General conditions and definitions

EESTI STANDARDI EESSÕNA

NATIONAL FOREWORD

See Eesti standard EVS-EN 62132-1:2016 sisaldab Euroopa standardi EN 62132-1:2016 ingliskeelset teksti.	This Estonian standard EVS-EN 62132-1:2016 consists of the English text of the European standard EN 62132-1:2016.
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English Version

**Integrated circuits - Measurement of electromagnetic immunity -
Part 1: General conditions and definitions
(IEC 62132-1:2015)**

Circuits intégrés - Mesure de l'immunité électromagnétique
- Partie 1: Conditions générales et définitions
(IEC 62132-1:2015)

Integrierte Schaltungen - Messung der elektromagnetischen
Störfestigkeit - Teil 1: Allgemeine Bedingungen und Begriffe
(IEC 62132-1:2015)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

European foreword

The text of document 47A/974/FDIS, future edition 2 of IEC 62132-1, prepared by SC 47A “Integrated circuits” of IEC/TC 47 “Semiconductor devices” was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62132-1:2016.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2016-09-03
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2018-12-03

This document supersedes EN 62132-1:2006.

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Endorsement notice

The text of the International Standard IEC 62132-1:2015 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 61400-4-3	NOTE	Harmonized as EN 61400-4-3.
IEC 61400-4-6	NOTE	Harmonized as EN 61400-4-6.
IEC 61967-1:2002	NOTE	Harmonized as EN 61967-1:2002.
CISPR 20	NOTE	Harmonized as EN 55020.

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 62132-2	-	Integrated circuits - Measurement of electromagnetic immunity -- Part 2: Measurement of radiated immunity - TEM cell and wideband TEM cell method	EN 62132-2	-
IEC 62132-3	-	Integrated circuits - Measurement of electromagnetic immunity, 150 kHz to 1 GHz -- Part 3: Bulk current injection (BCI) method	EN 62132-3	-
IEC 62132-4	-	Integrated circuits - Measurement of electromagnetic immunity, 150 kHz to 1 GHz -- Part 4: Direct RF power injection method	EN 62132-4	-
IEC 62132-5	-	Integrated circuits - Measurement of electromagnetic immunity, 150 kHz to 1 GHz -- Part 5: Workbench Faraday cage method	EN 62132-5	-
IEC 62132-8	-	Integrated circuits - Measurement of electromagnetic immunity -- Part 8: Measurement of radiated immunity - IC stripline method	EN 62132-8	-
IEC/TS 62132-9	-	Integrated circuits - Measurement of electromagnetic immunity - Part 9: Measurement of radiated immunity - Surface scan method	-	-

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INTRODUCTION

The IEC 62132 series is published in several parts, under the general title *Integrated circuits – Measurement of electromagnetic immunity*:

- Part 1: General conditions and definitions
- Part 2: Measurement of radiated immunity – TEM cell and wideband TEM cell method
- Part 3: Bulk current injection (BCI) method
- Part 4: Direct RF power injection method
- Part 5: Workbench Faraday cage method
- Part 8: Measurement of radiated immunity – IC stripline method
- Part 9: Measurement of radiated immunity – Surface scan method